

This Page Is Inserted by IFW Operations
and is not a part of the Official Record

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

IMAGES ARE BEST AVAILABLE COPY.

**As rescanning documents *will not* correct images,
please do not report the images to the
Image Problem Mailbox.**

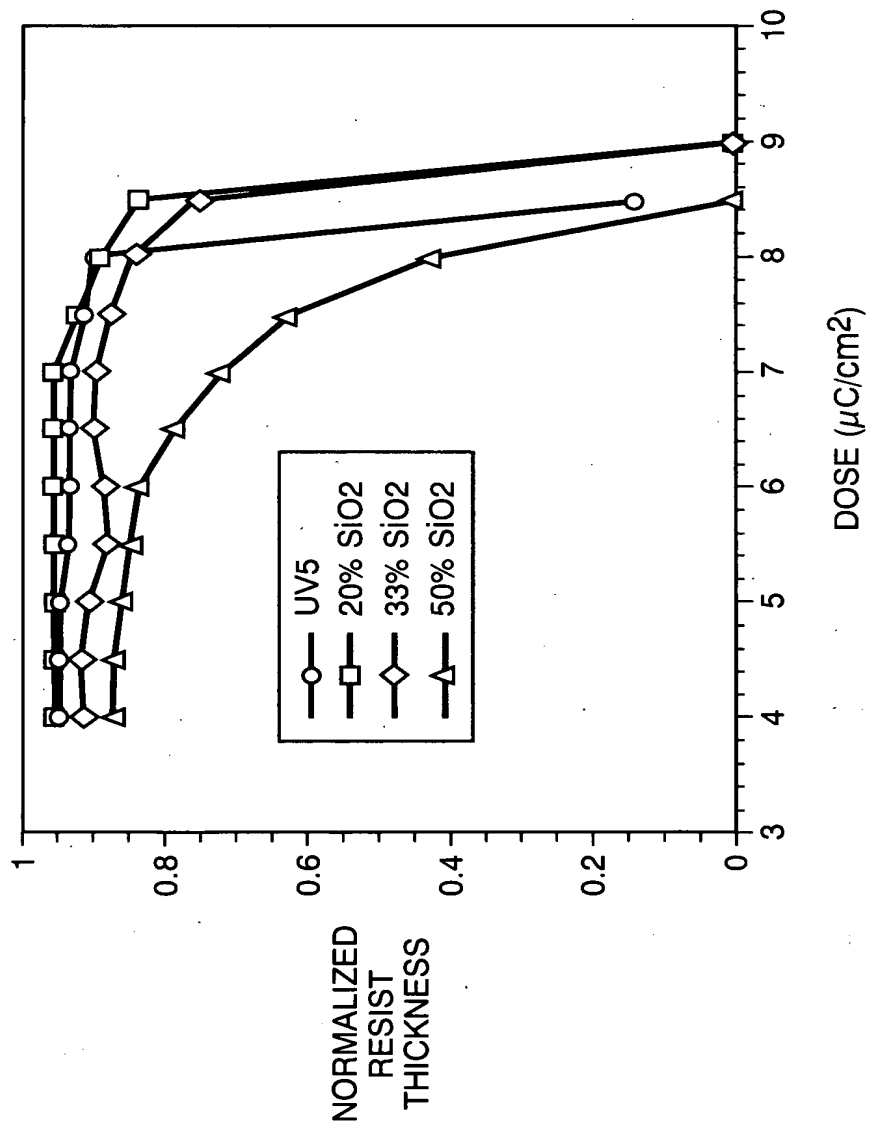
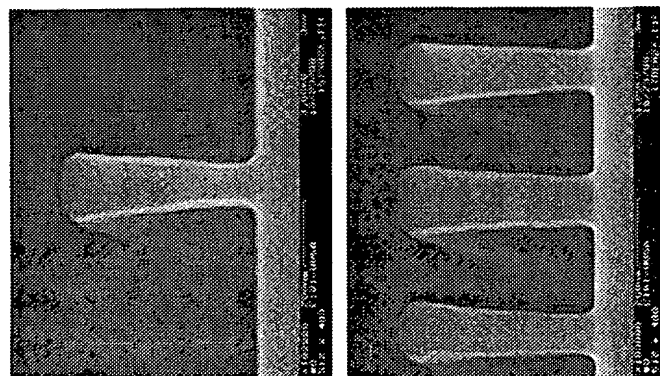
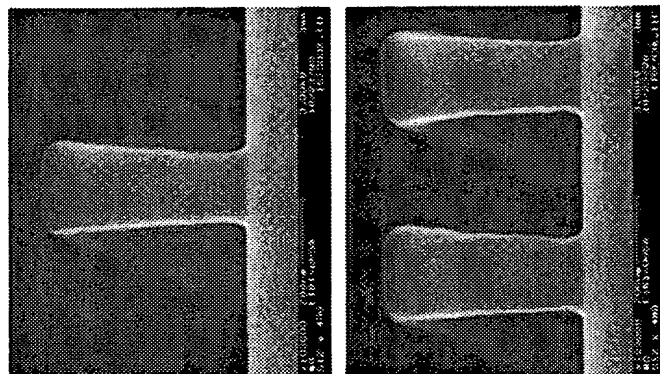


FIG. 1

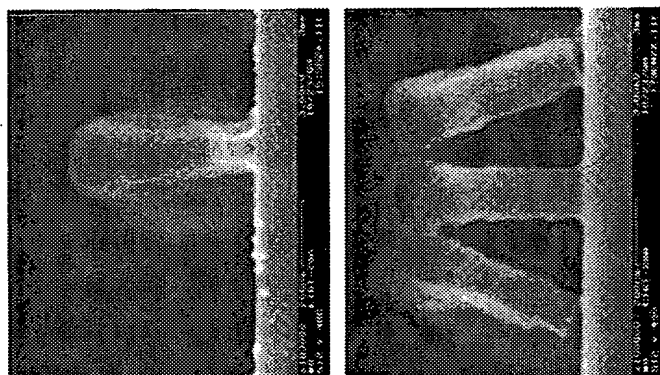
EXPERIMENTAL 20% SiO₂ EIRT RESIST



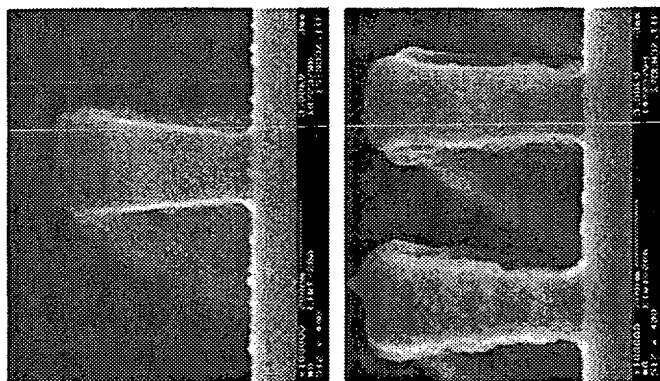
200 nm



300 nm



200 nm



300 nm

FIG. 2



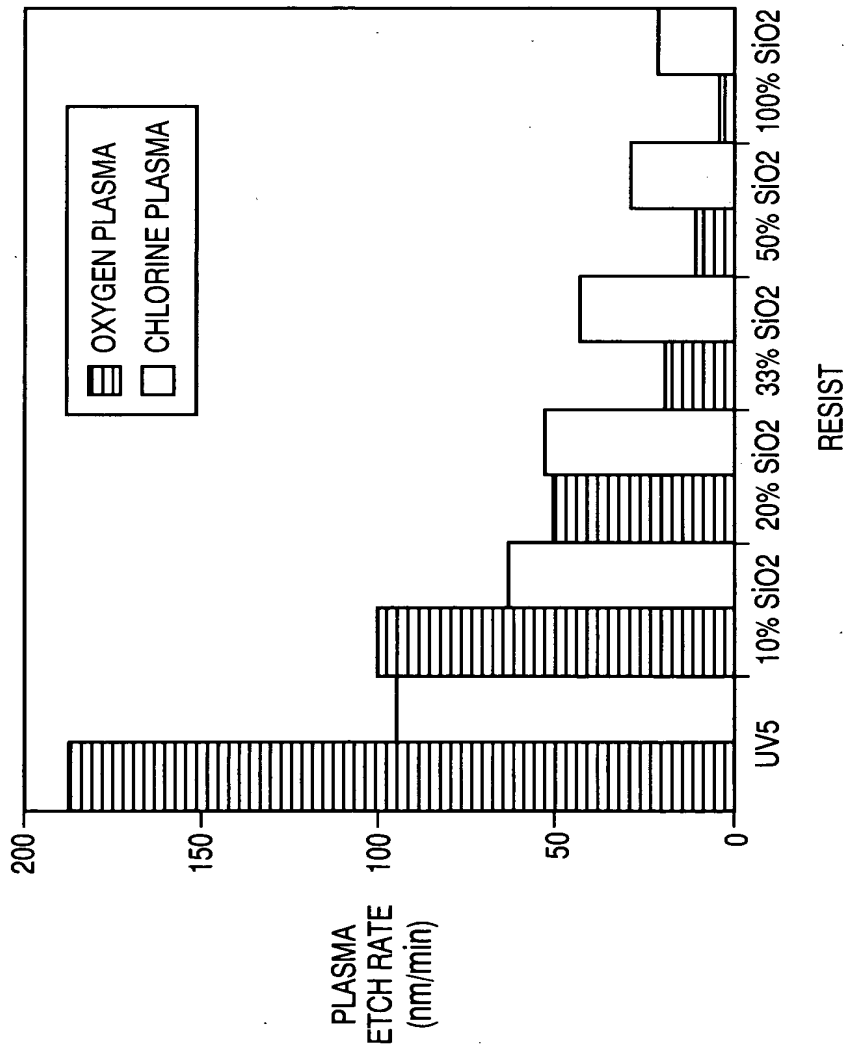
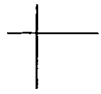


FIG. 3



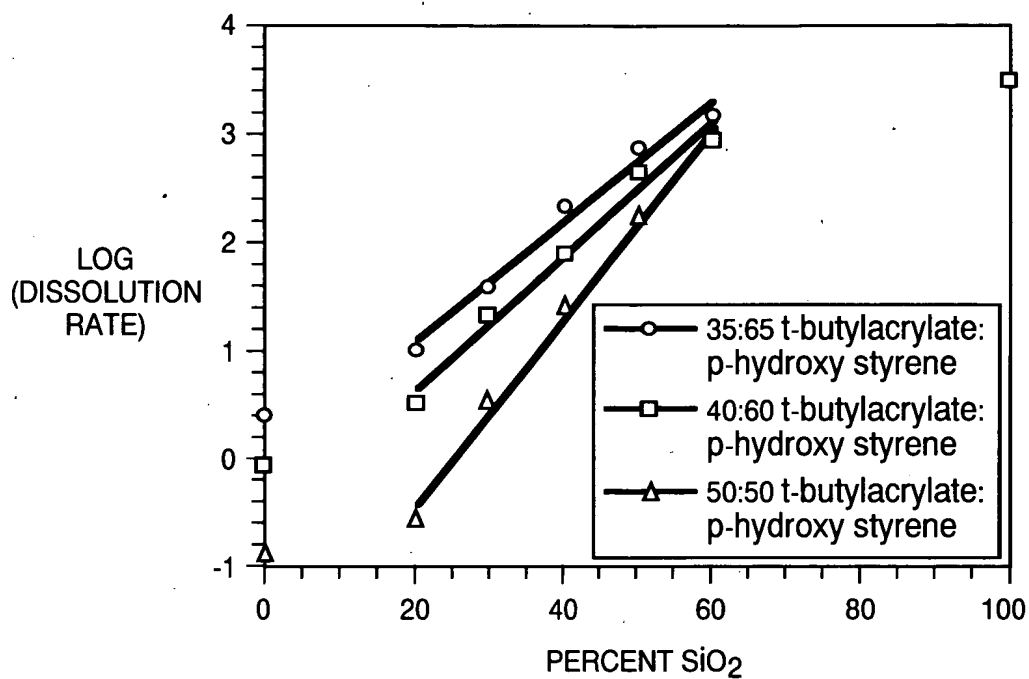


FIG. 4

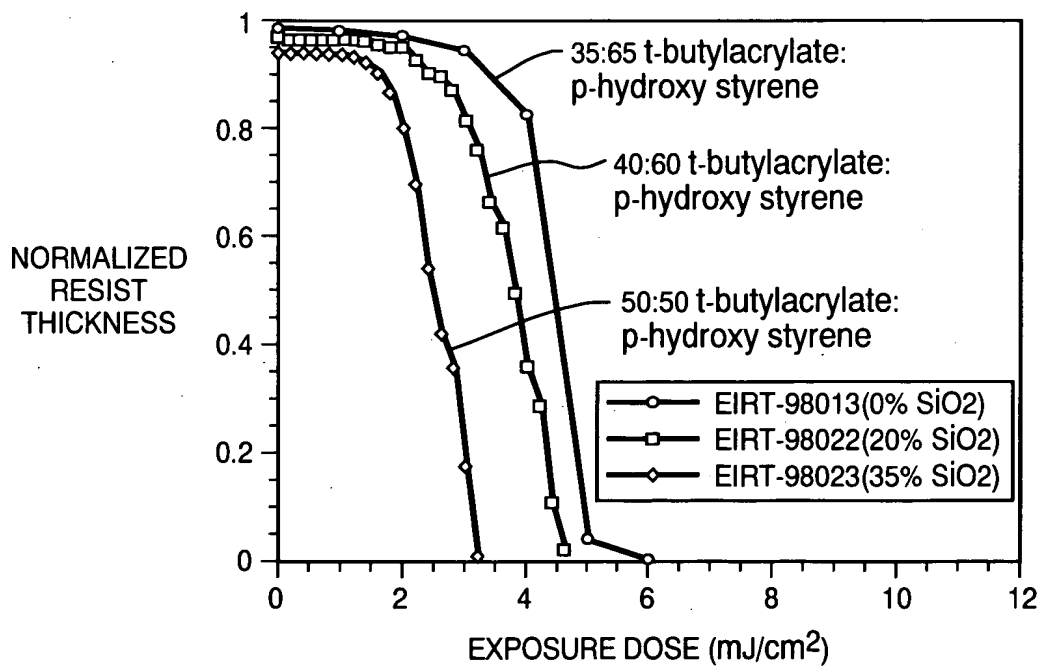
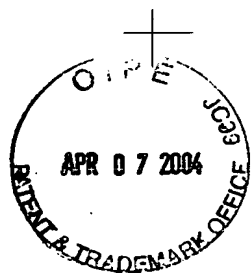
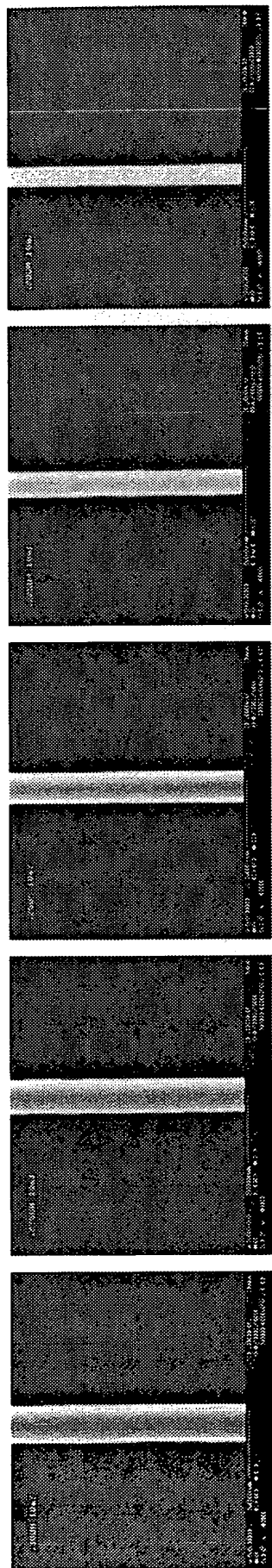
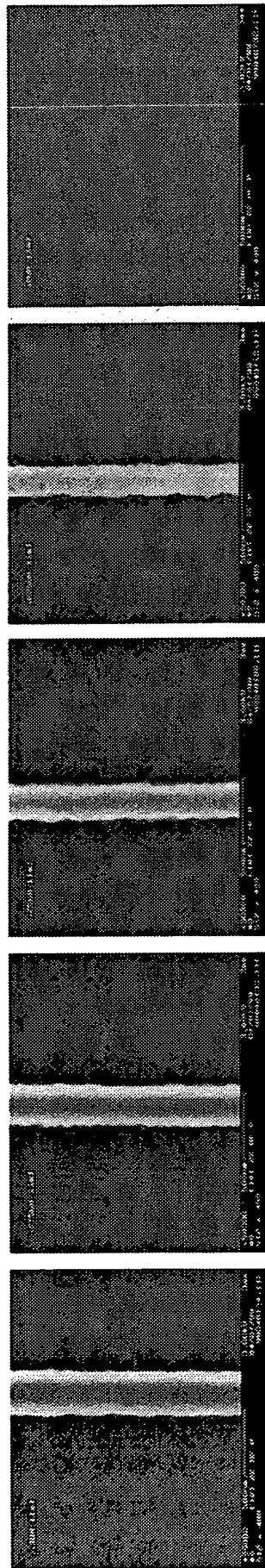


FIG. 5

EIRT 98013 RESIST (0% SiO₂) PREPARED FROM 35:65 T-BUTYLACRYLATE:P-HYDROXYSTYRENEEIRT 98022 RESIST (20% SiO₂) PREPARED FROM 40:60 T-BUTYLACRYLATE:P-HYDROXYSTYRENE

300 nm 275 nm 250 nm 225 nm 200 nm

FIG. 6